

ICS 31.080.1

CCS L 40



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 4937.1-2006

Replacing GB/T 4937-1995 Partial

**Semiconductor devices -- Mechanical and climatic test methods
-- Part 1: General
(English Translation)**

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What this standard covers

This standard applies to semiconductor devices (discrete devices and integrated circuits) and to GB/T 4937 series the rest of the establishment of common guidelines. When the part is too small walk back and forth with the corresponding specification when viewed with spears. In detail specification shall prevail.

Document data

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Standards quoted by this document

IEC 60050; IEC 60747; IEC 60748